Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/519,952	OH, JAE-WAN	
Examiner	Art Unit	
LOIS ZHENG	1793	

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventorship search	1/28/2008		
EAST search	1/28/2008	LLZ	
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